FCC Test Report

Project No.	:	1604014
Equipment	:	Micro SD Card
Model Name	:	Industrial microSD R1, Industrial microSDHC R1
Applicant	:	Apacer Technology Inc.
Address	:	1F., No.32, Zhongcheng Rd., Tucheng Dist. New Taipei City 236, Taiwan R.O.C

Date of Receipt	:	Mar. 04, 2016
Date of Test	:	Mar. 04, 2016 ~ Mar. 16, 2016
Issued Date	:	Apr. 13, 2016
Tested by	:	BTL Inc.

Testing Engineer : (Pike Lee)

Technical Manager : (Jeff Yang)

Authorized Signatory : (Andy Chiu)

BTL INC.

B1, No. 37, Lane 365, Yang-Guang St.,
Nei-Hu District, Taipei City 114, Taiwan.
TEL: +886-2-2657-3299 FAX: +886-2-2657-3331

Testing Laboratory
0659

Declaration

BTL represents to the client that testing is done in accordance with standard procedures as applicable and that test instruments used has been calibrated with standards traceable to international standard(s) and/or national standard(s).

BTL's reports apply only to the specific samples tested under conditions. It is manufacture's responsibility to ensure that additional production units of this model are manufactured with the identical electrical and mechanical components. **BTL** shall have no liability for any declarations, inferences or generalizations drawn by the client or others from **BTL** issued reports.

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BTL's laboratory quality assurance procedures are in compliance with the **ISO Guide 17025** requirements, and accredited by the conformity assessment authorities listed in this test report.

Limitation

For the use of the authority's logo is limited unless the Test Standard(s)/Scope(s)/Item(s) mentioned in this test report is (are) included in the conformity assessment authorities acceptance respective.

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REPORT ISSUED HISTORY

Issued No.	Description	Issued Date
BTL-FCCE-1-1603053	Original report.	Mar. 17, 2016
BTL-FCCE-1-1604014	Compared with the previous report (BTL-FCCE-1-1603053), model name, brand name and applicant information are changed, these changes have no effect on test result, and the rest are remained.	Apr. 13, 2016

1. CERIFICATION

Equipment	:	Micro SD Card
Brand Name	:	Apacer
Model Name	:	Industrial microSD R1, Industrial microSDHC R1
Applicant	:	Apacer Technology Inc.
Date of Test	:	Mar. 04, 2016 ~ Mar. 16, 2016
Test Sample	:	Engineering Sample
Standard(s)	:	FCC Part 15, Subpart B Class B ICES-003 Issue 6: 2016 Class B CAN/CSA-CISPR 22-10 Class B CISPR 22: 2008 Class B ANSI C63.4-2014

The above equipment has been tested and found compliance with the requirement of the relative standards by BTL Inc.
The test data, data evaluation, and equipment configuration contained in our test report (Ref No. BTL-FCCE-1-1604014) were obtained utilizing the test procedures, test instruments, test sites that has been accredited by the Authority of TAF according to the ISO-17025 quality assessment standard and technical standard(s).

2. SUMMARY OF TEST RESULTS

Test procedures according to the technical standard(s):

Emission				
Standard(s)	Test Item	Limit	Judgment	Remark
FCC Part 15,Subpart B ICES-003 Issue 6: 2016 CAN/CSA-CISPR 22-10 CISPR 22: 2008	Conducted emission	Class B	PASS	
	Radiated emission Below 1 GHz	Class B	PASS	
	Radiated emission Above 1 GHz	Class B	PASS	**NOTE (2)**

NOTE:

(1) ”N/A” denotes test is not applicable in this test report.

(2) The EUT’s max operating frequency is 208MHz which exceeds 108 MHz, so the test will be performed.

2.1 TEST FACILITY

The test facilities used to collect the test data in this report:

Conducted emission Test:

C05: (VCCI RN: C-4742; FCC RN:965108; FCC DN:TW1082)
No. 68-1, Ln. 169, Sec.2, Datong Rd., Xizhi Dist., New Taipei City 221, Taiwan

Radiated emission Test (Below 1 GHz):

OS02: (VCCI RN: R-2669; FCC RN: 95335; FCC DN: TW1010; IC Assigned Code: 4428A-1)
No.132-1, Ln. 329, Sec. 2, Balian Rd., Xizhi Dist., New Taipei City 221, Taiwan (R.O.C.)

Radiated emission Test (Above 1 GHz):

CB11: (VCCI RN: G-868)
No. 68-1, Ln. 169, Sec.2, Datong Rd., Xizhi Dist., New Taipei City 221, Taiwan

2.2 MEASUREMENT UNCERTAINTY

The measurement uncertainty is not specified by FCC/ Industry Canada rules and for reference only.

The reported uncertainty of measurement **y** ± **U**, where expanded uncertainty **U** is based on a standard uncertainty multiplied by a coverage factor of **k=2**, providing a level of confidence of approximately **95**%.

The measurement instrumentation uncertainty considerations contained in CISPR 16-4-2.

The BTL measurement uncertainty is less than the CISPR 16-4-2 U_{cispr} requirement.

A. Conducted emission test:

Test Site	Method	Measurement Frequency Range	U, (dB)
C05	CISPR	150 kHz~30MHz	2.04

B. Radiated emission test:

Test Site	Method	Measurement Frequency Range	Ant. H / V	U, (dB)
OS02 (10m)	CISPR	30 MHz ~ 200 MHz	V	3.08
		30 MHz ~ 200 MHz	H	3.40
		200 MHz ~ 1, 000 MHz	V	3.28
		200 MHz ~ 1, 000 MHz	H	3.72

Test Site	Method	Measurement Frequency Range	Ant. H / V	U, (dB)
CB11 (3m)	CISPR	1GHz ~ 6GHz	V	4.14
		1GHz ~ 6GHz	H	4.14
		6GHz ~ 18GHz	V	5.34
		6GHz ~ 18GHz	H	5.34

Note: Unless specifically mentioned, the uncertainty of measurement has not been taken into account to declare the compliance or non-compliance to the specification.

Our calculated Measurement Instrumentation Uncertainty is shown in the tables above.

These are our U_{lab} values in CISPR 16-4-2 terminology.

Since Table 1 of CISPR 16-4-2 has values of measurement instrumentation uncertainty, called U_{CISPR}, as follows:

Conducted Disturbance (mains port) – 150 kHz – 30 MHz : 3.6 dB

Radiated Disturbance (electric field strength on an open area test site or alternative test site) – 30 MHz – 1000 MHz : 5.2 dB

It can be seen that our U_{lab} values are smaller than U_{CISPR}.

3. GENERAL INFORMATION

3.1 GENERAL DESCRIPTION OF EUT

Equipment	Micro SD Card
Brand Name	Apacer
Model Name	Industrial microSD R1, Industrial microSDHC R1
Model Difference	Differ in market area.
Power Source	Supplied from host system.
Power Rating	EUT I/P: DC 5V

Note:

1. For a more detailed features description, please refer to the manufacturer's specifications or the user's manual.

3.2 DESCRIPTION OF TEST MODES

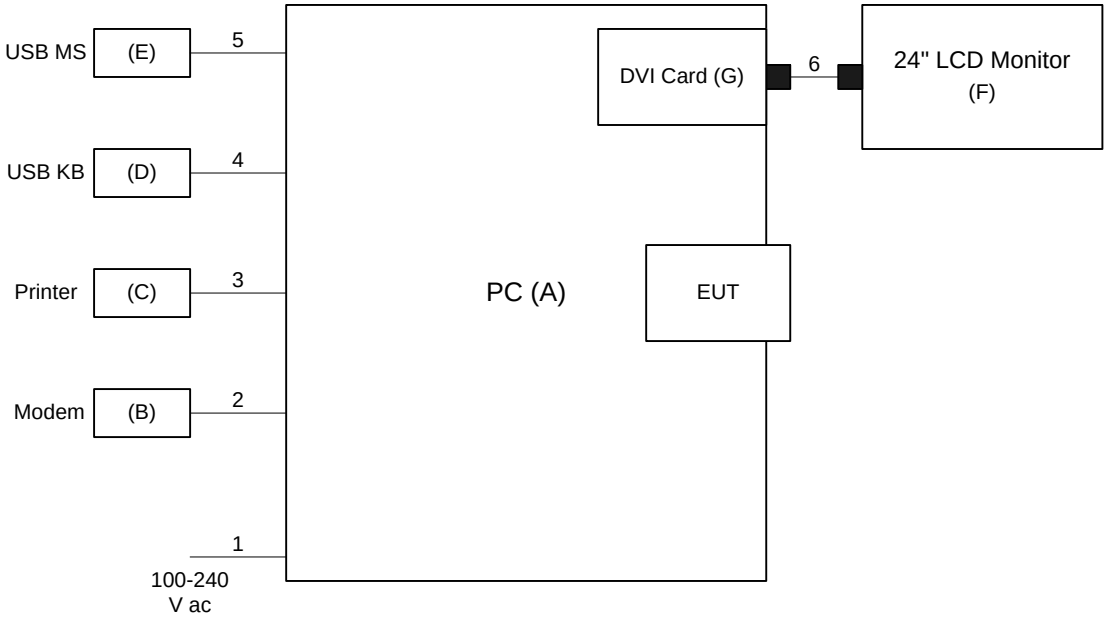
To investigate the maximum EMI emission characteristics generates from EUT, the test system was pre-scanning tested base on the consideration of following EUT operation mode or test configuration mode which possible have effect on EMI emission level. Each of these EUT operation mode(s) or test configuration mode(s) mentioned above was evaluated respectively.

Pretest Mode	Description
Mode 1	Micro SD CARD R/W

Conducted emission test	
Final Test Mode	Description
Mode 1	Micro SD CARD R/W

Radiated emission test	
Final Test Mode	Description
Mode 1	Micro SD CARD R/W

3.3 BLOCK DIAGRAM SHOWING THE CONFIGURATION OF SYSTEM TESTED



■ Ferrite core

3.4 DESCRIPTION OF SUPPORT UNITS

The EUT has been tested as an independent unit together with other necessary accessories or support units. The following support units or accessories were used to form a representative test configuration during the tests.

Item	Equipment	Brand	Model/Type No.	FCC ID	Series No.
A	PC	DELL	OptiPlex 790 MT	DOC	64NJVBX
B	Modem	ACEEX	DM-1414V	DOC	8041708
C	Printer	HP	SNPRB-1202-01	DOC	CN5161909P
D	USB K/B	DELL	L50U	DOC	CN-0H9F99-65890-17P-06WP-A01
E	USB Mouse	DELL	MS111-L	DOC	CN-09RRC7-44751-17J-OH1F
F	24" LCD Monitor	DELL	U2410f	DOC	CN-OJ257M-72872-09J-067L
G	DVI Card	ASUS	GTX 750 Ti	DOC	F3COYZ138369

Item	Shielded Type	Ferrite Core	Length	Note
1	NO	NO	1.7m	Power Cable
2	YES	NO	1.7m	RS232 Cable
3	YES	NO	1.7m	USB Cable
4	YES	NO	1.7m	USB Cable
5	YES	NO	1.7m	USB Cable
6	YES	YES	1.7m	DVI Cable

Note:

(1) The support equipment was authorized by Declaration of Conformity (DOC).

4. EMC EMISSION TEST

4.1 CONDUCTED EMISSION TEST

4.1.1 LIMITS (FREQUENCY RANGE 150 KHZ-30MHZ)

FREQUENCY (MHz)	Class A (dBuV)		Class B (dBuV)	
	Quasi-peak	Average	Quasi-peak	Average
0.15 - 0.5	79.00	66.00	66 - 56 *	56 - 46 *
0.50 - 5.0	73.00	60.00	56.00	46.00
5.0 - 30.0	73.00	60.00	60.00	50.00

NOTE:

(1) The tighter limit applies at the band edges.
(2) The limit of " * " marked band means the limitation decreases linearly with the logarithm of the frequency in the range.
(3) The test result calculated as following:
Measurement Value = Reading Level + Correct Factor
Correct Factor = Insertion Loss + Cable Loss + Attenuator Factor(if use)
Margin Level = Measurement Value – Limit Value

4.1.2 MEASUREMENT INSTRUMENTS LIST

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Calibrated until
1	TWO-LINE V-NETWORK	R&S	ENV216	100087	Jan. 25, 2017
2	Test Cable	TIMES	CFD300-NL	C05	Jun. 14, 2016
3	EMI Test Receiver	R&S	ESR7	101433	Dec. 09, 2016
4	Measurement Software	EZ	EZ_EMC (Version NB-03A)	N/A	N/A

Remark: “N/A” denotes no model name, serial no. or calibration specified.
All calibration period of equipment list is one year.

4.1.3 TEST PROCEDURE

a. The EUT was placed 0.8 meters from the horizontal ground plane with EUT being connected to the power mains through a line impedance stabilization network (LISN). All other support equipments powered from additional LISN(s). The LISN provide 50 Ohm/ 50uH of coupling impedance for the measuring instrument.
b. Interconnecting cables that hang closer than 40 cm to the ground plane shall be folded back and forth in the center forming a bundle 30 to 40 cm long.
c. I/O cables that are not connected to a peripheral shall be bundled in the center. The end of the cable may be terminated, if required, using the correct terminating impedance. The overall length shall not exceed 1 m.
d. LISN at least 80 cm from nearest part of EUT chassis.
e. For the actual test configuration, please refer to the related Item –EUT Test Photos.

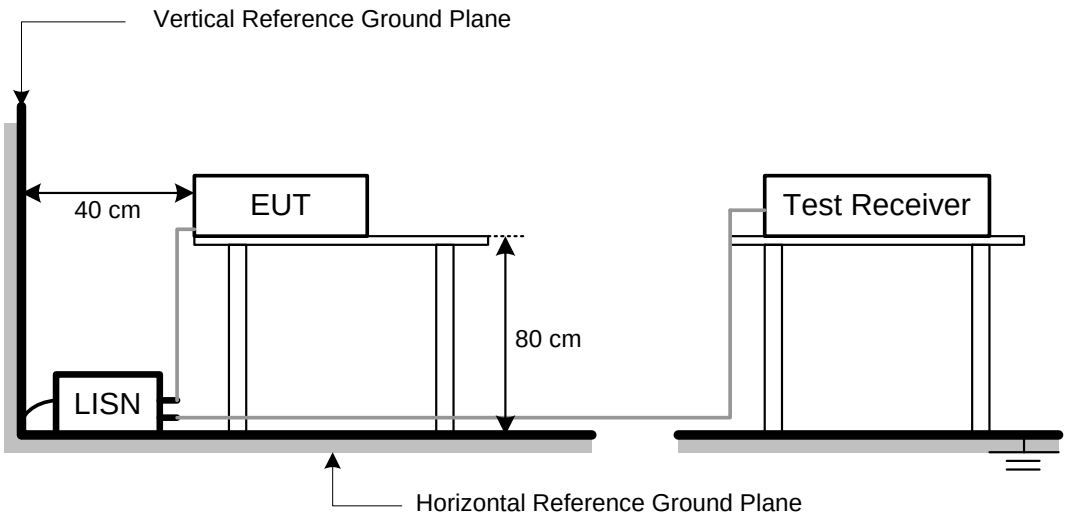
NOTE:

a. Reading in which marked as Peak, QP or AVG means measurements by using are Quasi-Peak or Average Mode with Detector BW=9 kHz (6 dB Bandwidth).
b. All readings are Peak Mode value unless otherwise stated QP or AVG in column of Note. If the Peak or QP Mode Measured value compliance with the QP Limits and lower than AVG Limits, the EUT shall be deemed to meet both QP & AVG Limits and then only Peak or QP Mode was measured, but AVG Mode didn‘t perform.

4.1.4 DEVIATION FROM TEST STANDARD

No deviation

4.1.5 TEST SETUP



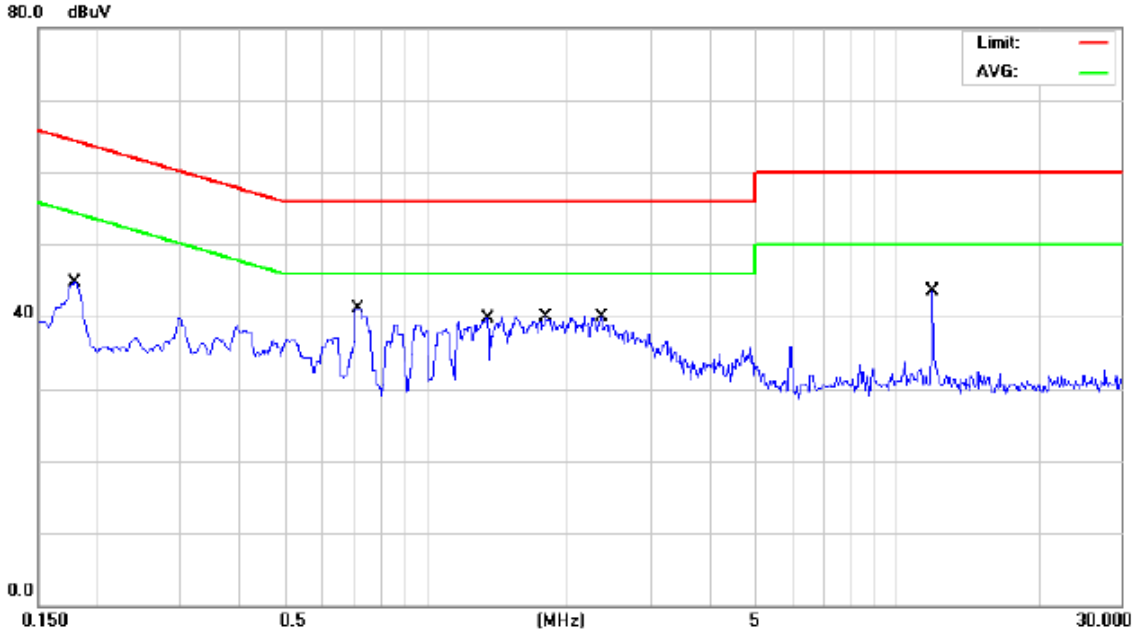
4.1.6 EUT OPERATING CONDITIONS

The PC exercise program (BurninTEST V7.1) used during radiated and/or conducted emission measurement was designed to exercise the various system components in a manner similar to a typical use.

4.1.7 TEST RESULTS

EUT	Micro SD Card	Model Name	Industrial microSD R1
Temperature	25°C	Relative Humidity	54%
Test Voltage	AC 120V/60Hz		
Test Mode	Micro SD CARD R/W		

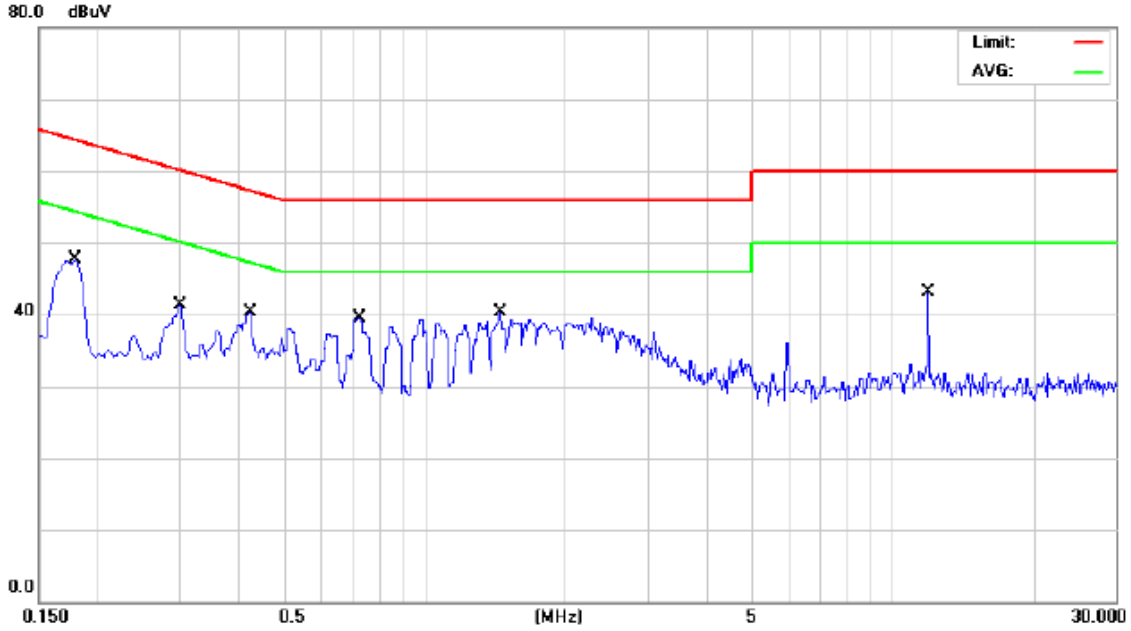
Phase: Line



No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Margin		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.1794	28.60	9.66	38.26	64.51	-26.25	QP	
2		0.1794	23.90	9.66	33.56	54.51	-20.95	AVG	
3		0.7160	24.00	9.69	33.69	56.00	-22.31	QP	
4		0.7160	16.50	9.69	26.19	46.00	-19.81	AVG	
5		1.3460	25.40	9.72	35.12	56.00	-20.88	QP	
6		1.3460	14.20	9.72	23.92	46.00	-22.08	AVG	
7		1.7960	25.10	9.75	34.85	56.00	-21.15	QP	
8		1.7960	11.40	9.75	21.15	46.00	-24.85	AVG	
9		2.3540	23.70	9.77	33.47	56.00	-22.53	QP	
10		2.3540	11.40	9.77	21.17	46.00	-24.83	AVG	
11		11.9000	32.60	9.90	42.50	60.00	-17.50	QP	
12	*	11.9000	32.20	9.90	42.10	50.00	-7.90	AVG	

EUT	Micro SD Card	Model Name	Industrial microSD R1
Temperature	25°C	Relative Humidity	54%
Test Voltage	AC 120V/60Hz		
Test Mode	Micro SD CARD R/W		

Phase: Neutral



No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Margin		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.1794	33.40	9.66	43.06	64.51	-21.45	QP	
2		0.1794	30.10	9.66	39.76	54.51	-14.75	AVG	
3		0.2991	22.40	9.67	32.07	60.27	-28.20	QP	
4		0.2991	18.30	9.67	27.97	50.27	-22.30	AVG	
5		0.4216	21.00	9.67	30.67	57.42	-26.75	QP	
6		0.4216	15.80	9.67	25.47	47.42	-21.95	AVG	
7		0.7250	24.30	9.69	33.99	56.00	-22.01	QP	
8		0.7250	16.90	9.69	26.59	46.00	-19.41	AVG	
9		1.4540	24.80	9.72	34.52	56.00	-21.48	QP	
10		1.4540	12.00	9.72	21.72	46.00	-24.28	AVG	
11		11.9000	32.50	9.91	42.41	60.00	-17.59	QP	
12	*	11.9000	32.10	9.91	42.01	50.00	-7.99	AVG	

4.2 RADIATED EMISSION TEST

4.2.1 LIMITS

Below 1 GHz

Measurement Method and Applied Limits:

ANSI C63.4:

Frequency (MHz)	Class A (at 10m)		Class B (at 3m)	
	(uV/m) Field strength	(dBuV/m) Field strength	(uV/m) Field strength	(dBuV/m) Field strength
30 - 88	90	39	100	40
88 - 216	150	43.5	150	43.5
216 - 960	210	46.4	200	46
Above 960	300	49.5	500	54

CISPR 22 or CAN/CSA-CISPR 22-10:

Frequency (MHz)	Class A (at 10m)	Class B (at 10m)
	dBuV/m	dBuV/m
30 - 230	40	30
230 - 1000	47	37

Above 1 GHz

Measurement Method and Applied Limits:

ANSI C63.4:

Frequency (MHz)	Class A				Class B	
	(dBuV/m) (at 3m)		(dBuV/m) (at 10m)		(dBuV/m) (at 3m)	
	Peak	Average	Peak	Average	Peak	Average
Above 1000	80	60	69.5	49.5	74	54

FREQUENCY RANGE OF RADIATED MEASUREMENT (FOR UNINTENTIONAL RADIATORS)

Highest frequency generated or Upper frequency of measurement used in the device or on which the device operates or tunes (MHz)	Range (MHz)
Below 1.705	30
1.705 - 108	1000
108 - 500	2000
500 - 1000	5000
Above 1000	5th harmonic of the highest frequency or 40 GHz, whichever is lower

NOTE:

(1) The limit for radiated test was performed according to as following:
FCC Part 15, Subpart B. ICES-003 Issue 6: 2016.

(2) The tighter limit applies at the band edges.

(3) Emission level (dBuV/m) = 20log Emission level (uV/m).
3m Emission level = 10m Emission level + 20log(10m/3m).

(4) The test result calculated as following:
Measurement Value = Reading Level + Correct Factor
Correct Factor = Antenna Factor + Cable Loss - Amplifier Gain(if use)
Margin Level = Measurement Value - Limit Value

4.2.2 MEASUREMENT INSTRUMENTS LIST

Below 1 GHz:

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Calibrated until
1	Log-Bicon Antenna	Schwarzbeck	VULB 9160	3173	Dec. 03, 2016
2	Pre-Amplifier	Anritsu	MH648A	M98457	May 27, 2016
3	Test Cable	TIMES	LMR-400	10M-OS01	May 27, 2016
4	Test Cable	TIMES	LMR-400	OS02	May 27, 2016
5	EMI Test Receiver	R&S	ESCI	100082	N/A
6	System Controller (OS02)	CT	SC100	N/A	N/A
7	Turn Table	Chance Most	CMTB-1.5	N/A	N/A
8	Measurement Software	EZ	EZ_EMC (Version NB-03A)	N/A	N/A

Above 1 GHz:

1	Horn Antenna	Schwarzbeck	BBHA-9120D	D 546	Nov. 04, 2016
2	Pre-Amplifier	Agilent	8449B	3008A02331	Jan. 22, 2017
3	Test Cable	EMCI	EMC104-SM-SM-5000	140302	Mar. 08, 2017
4	Test Cable	EMCI	EMC104-SM-SM-2500	150306	Mar. 08, 2017
5	Test Cable	EMCI	EMC104-SM-SM-800	150305	Mar. 08, 2017
6	EMI Test Receiver	R&S	N9038A	MY51210215	Jun. 07, 2016
7	Measurement Software	Farad	EZ_EMC (Version NB-03A)	N/A	N/A

Remark: “N/A” denotes no model name, serial no. or calibration specified.
All calibration period of equipment list is one year.

4.2.3 TEST PROCEDURE

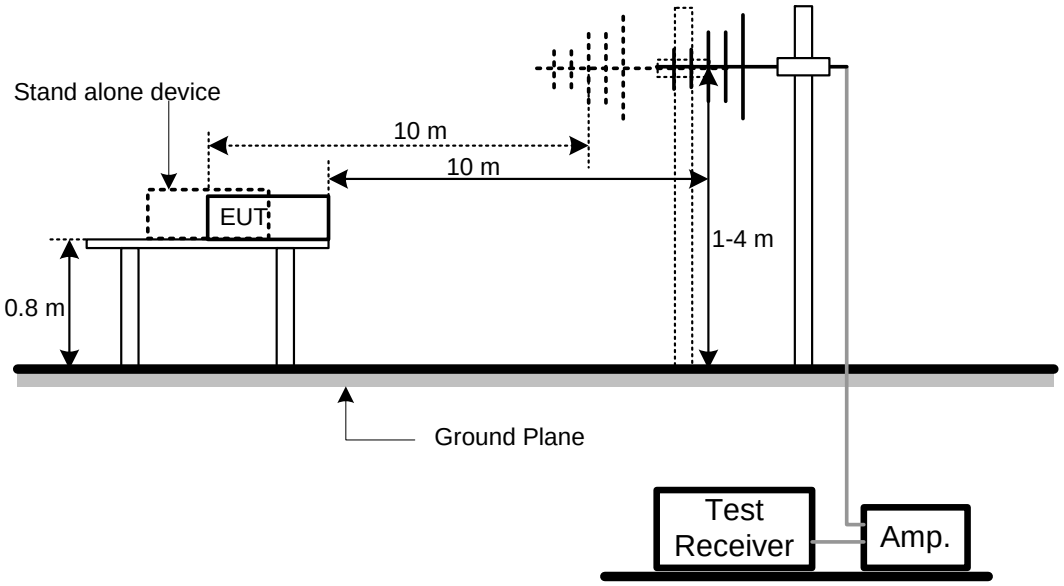
a. The measuring distance of 10 m shall be used for measurements. The EUT was placed on the top of a rotating table 0.8 meter above the ground at a 10 meter open area test site. The table was rotated 360 degrees to determine the position of the highest radiation.(below 1GHz)
b. The measuring distance of 3 m shall be used for measurements. The EUT was placed on the top of a rotating table 0.8 meter above the ground at a 3 meter semi-anechoic chamber. The table was rotated 360 degrees to determine the position of the highest radiation.(above 1GHz)
c. The height of the equipment or of the substitution antenna shall be 0.8 m, the height of the test antenna shall vary between 1 m to 4 m. Both horizontal and vertical polarizations of the antenna are set to make the measurement.
d. For each suspected emission, the EUT was arranged to its worst case and then the antenna was tuned to heights find the maximum reading (used Bore sight function).
e. The receiver system was set to peak and average detect function and specified bandwidth with maximum hold mode when the test frequency is above 1GHz.
f. The initial step in collecting radiated emission data is a receiver peak detector mode pre-scanning the measurement frequency range. Significant peaks are then marked and then Quasi Peak detector mode re-measured.
g. All readings are Peak unless otherwise stated QP in column of Note. Peak denotes that the Peak reading compliance with the QP Limits and then QP Mode measurement didn‘t perform. (below 1GHz)
h. All readings are Peak Mode value unless otherwise stated AVG in column of Note. If the Peak Mode Measured value compliance with the Peak Limits and lower than AVG Limits, the EUT shall be deemed to meet both Peak & AVG Limits and then only Peak Mode was measured, but AVG Mode didn‘t perform. (above 1GHz)
i. For the actual test configuration, please refer to the related Item –EUT Test Photos.

4.2.4 DEVIATION FROM TEST STANDARD

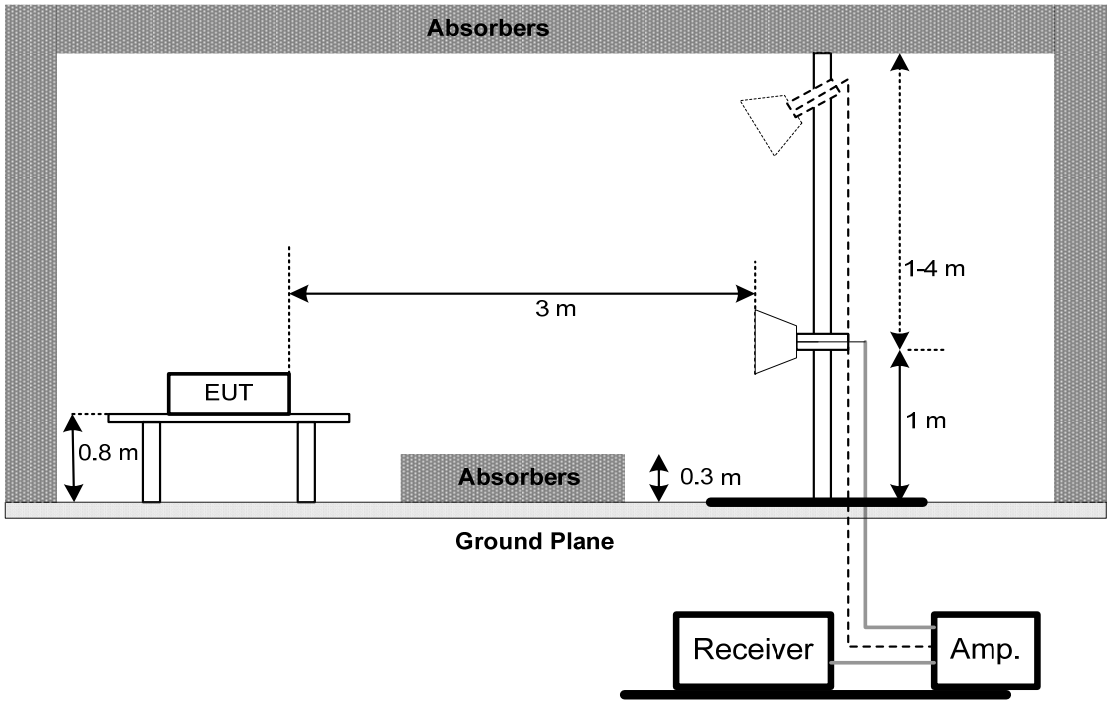
No deviation

4.2.5 TEST SETUP

Below 1 GHz



Above 1 GHz



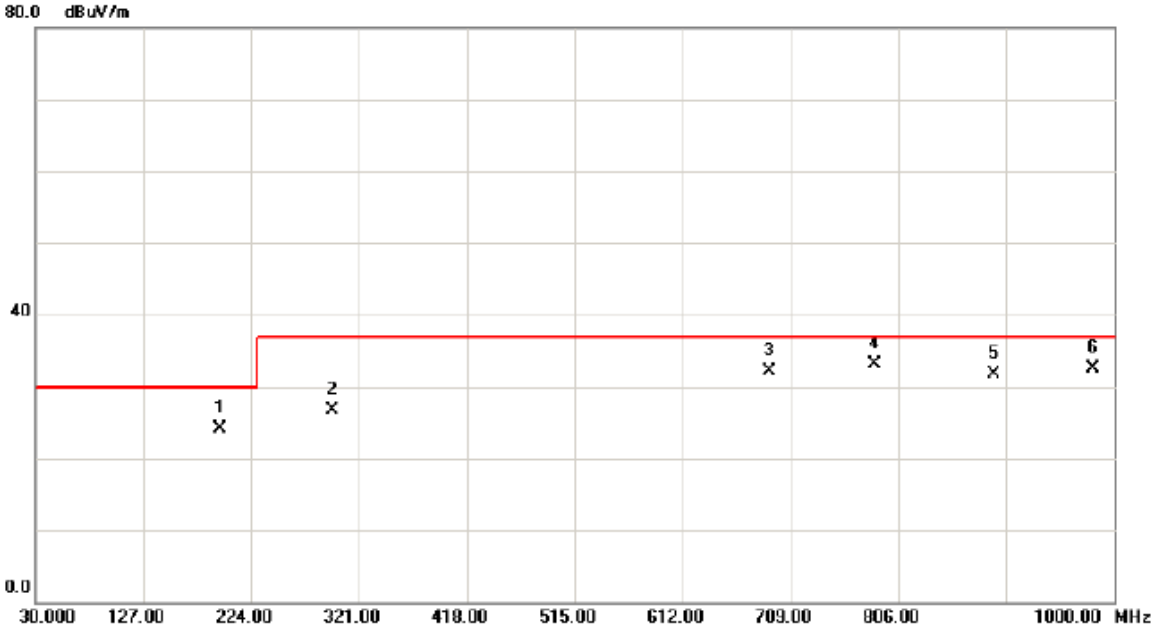
4.2.6 EUT OPERATING CONDITIONS

The EUT tested system was configured as the statements of **4.1.6** unless otherwise a special operating condition is specified in the follows during the testing.

4.2.7 TEST RESULTS-BELOW 1 GHZ

EUT	Micro SD Card	Model Name	Industrial microSD R1
Temperature	17° C	Relative Humidity	63%
Test Voltage	AC 120V/60Hz		
Test Mode	Micro SD CARD R/W		

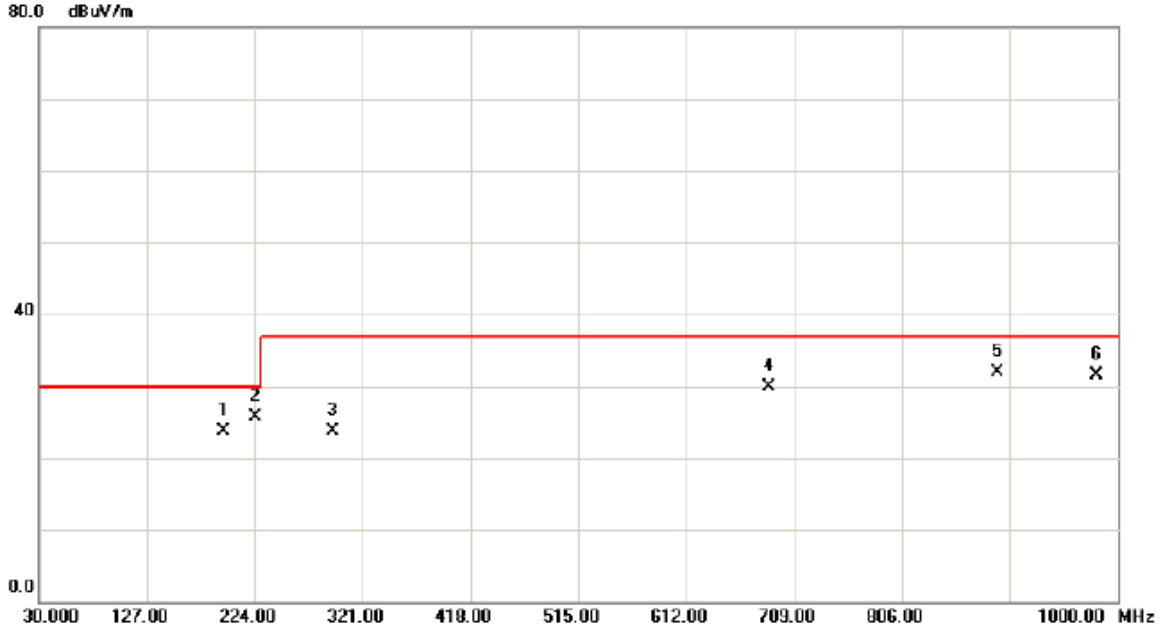
Polarization: Vertical



No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	cm	degree	Comment
1		195.3600	31.66	-7.59	24.07	30.00	-5.93	QP	100	0	
2		296.3200	30.63	-3.95	26.68	37.00	-10.32	QP	120	86	
3		689.2100	27.85	4.21	32.06	37.00	-4.94	QP	150	47	
4	*	784.2200	26.55	6.53	33.08	37.00	-3.92	QP	100	186	
5		891.6300	23.54	8.09	31.63	37.00	-5.37	QP	100	95	
6		980.5600	22.74	9.86	32.60	37.00	-4.40	QP	150	56	

EUT	Micro SD Card	Model Name	Industrial microSD R1
Temperature	17° C	Relative Humidity	63%
Test Voltage	AC 120V/60Hz		
Test Mode	Micro SD CARD R/W		

Polarization: Horizontal

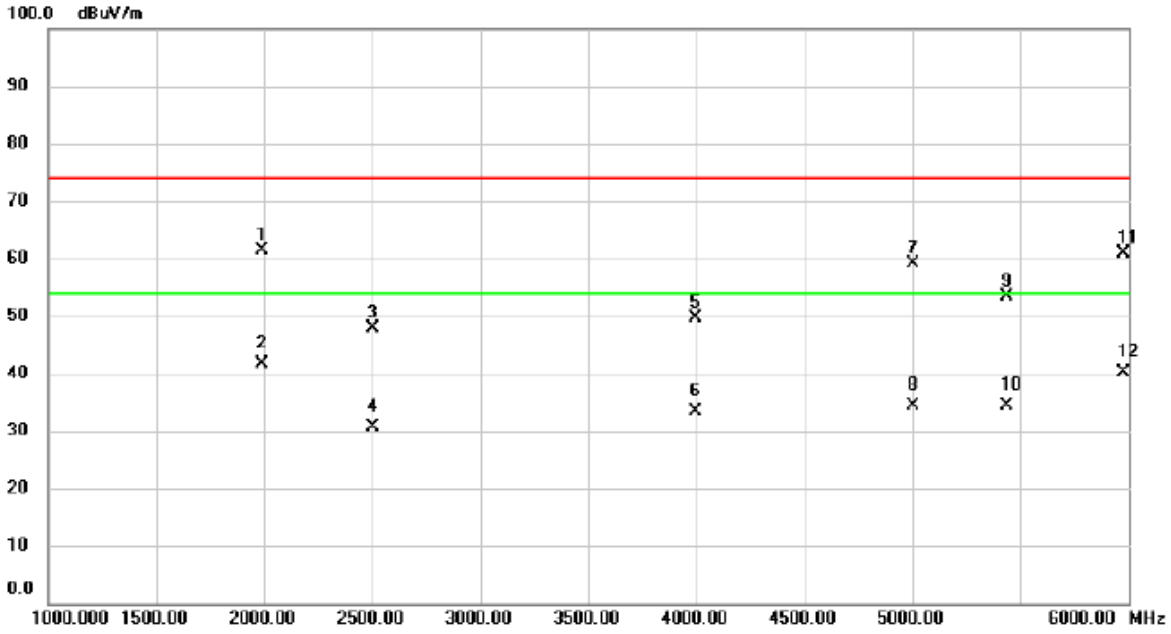


No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	cm	degree	Comment
1		195.0300	31.33	-7.57	23.76	30.00	-6.24	QP	200	96	
2	*	224.5600	32.59	-6.87	25.72	30.00	-4.28	QP	250	0	
3		293.6300	27.63	-3.97	23.66	37.00	-13.34	QP	200	187	
4		685.4100	25.66	4.16	29.82	37.00	-7.18	QP	200	93	
5		891.4200	23.74	8.08	31.82	37.00	-5.18	QP	260	85	
6		979.6600	21.56	9.85	31.41	37.00	-5.59	QP	220	247	

4.2.8 TEST RESULTS-ABOVE 1 GHZ

EUT	Micro SD Card	Model Name	Industrial microSD R1
Temperature	26° C	Relative Humidity	61%
Test Voltage	AC 120V/60Hz		
Test Mode	Micro SD CARD R/W		

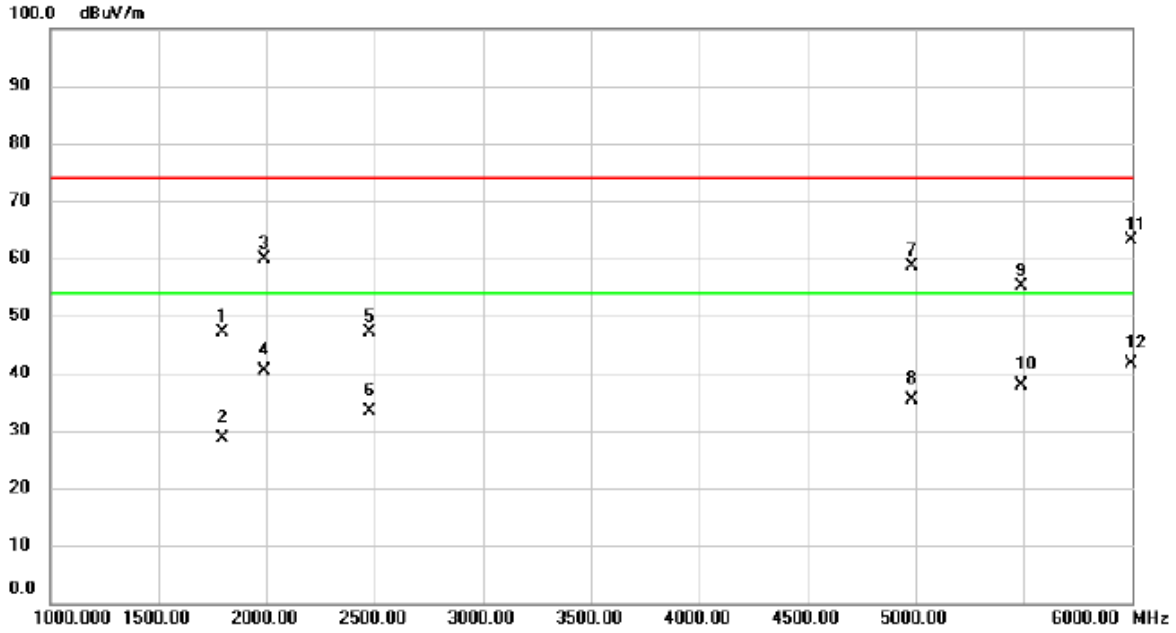
Polarization: Vertical



No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Margin		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	cm	degree	Comment
1		1990.000	66.09	-4.72	61.37	74.00	-12.63	peak	100	222	
2	*	1990.000	46.35	-4.72	41.63	54.00	-12.37	AVG	100	222	
3		2500.000	50.82	-2.88	47.94	74.00	-26.06	peak	200	18	
4		2500.000	33.61	-2.88	30.73	54.00	-23.27	AVG	200	18	
5		3995.000	48.90	0.79	49.69	74.00	-24.31	peak	100	203	
6		3995.000	32.70	0.79	33.49	54.00	-20.51	AVG	100	203	
7		5000.000	55.40	3.76	59.16	74.00	-14.84	peak	100	145	
8		5000.000	30.61	3.76	34.37	54.00	-19.63	AVG	100	145	
9		5435.000	48.76	4.57	53.33	74.00	-20.67	peak	200	155	
10		5435.000	29.72	4.57	34.29	54.00	-19.71	AVG	200	155	
11		5975.000	55.65	5.16	60.81	74.00	-13.19	peak	200	204	
12		5975.000	35.08	5.16	40.24	54.00	-13.76	AVG	200	204	

EUT	Micro SD Card	Model Name	Industrial microSD R1
Temperature	26° C	Relative Humidity	61%
Test Voltage	AC 120V/60Hz		
Test Mode	Micro SD CARD R/W		

Polarization: Horizontal



No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Margin		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	cm	degree	Comment
1		1795.000	52.17	-5.16	47.01	74.00	-26.99	peak	100	48	
2		1795.000	33.70	-5.16	28.54	54.00	-25.46	AVG	100	48	
3		1990.000	64.68	-4.72	59.96	74.00	-14.04	peak	200	321	
4		1990.000	45.02	-4.72	40.30	54.00	-13.70	AVG	200	321	
5		2475.000	49.98	-2.97	47.01	74.00	-26.99	peak	200	159	
6		2475.000	36.44	-2.97	33.47	54.00	-20.53	AVG	200	159	
7		4985.000	54.85	3.72	58.57	74.00	-15.43	peak	200	11	
8		4985.000	31.72	3.72	35.44	54.00	-18.56	AVG	200	11	
9		5490.000	50.58	4.67	55.25	74.00	-18.75	peak	100	114	
10		5490.000	33.31	4.67	37.98	54.00	-16.02	AVG	100	114	
11	*	5995.000	57.90	5.18	63.08	74.00	-10.92	peak	100	350	
12		5995.000	36.37	5.18	41.55	54.00	-12.45	AVG	100	350	

5. EUT TEST PHOTO

Conducted emission test photos

Micro SD CARD R/W

Radiated emission below 1 GHz test photos

Micro SD CARD R/W

Radiated emission above 1 GHz test photos

Micro SD CARD R/W